

日立FIB⇔FE-SEM共用試料ホルダ MI4050 ⇔ Regulus/SU8200/SU8000/etc.

Hitachi FIB⇔FE-SEM compatible sample holder

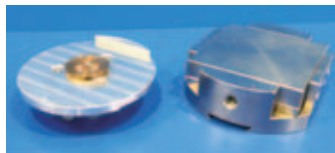
FIB加工～SEM観察/分析の スループットを改善!



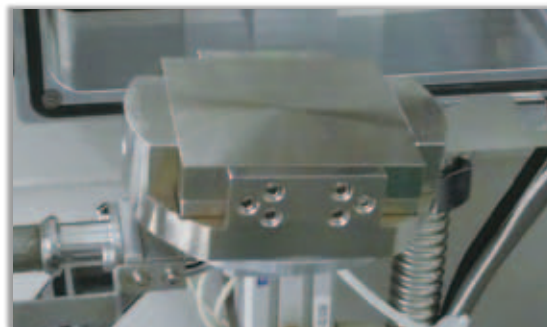
Enhanced throughput for FIB milling and SEM imaging/analysis !

- 共用試料ホルダにより、MI4050用試料台をワンタッチで日立FE-SEMに導入可能。

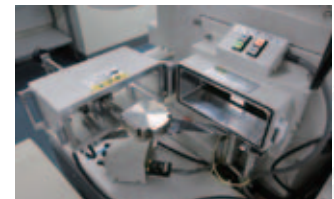
Compatible sample holder allows single-action introduction of MI4050 sample stub to Hitachi FE-SEM.



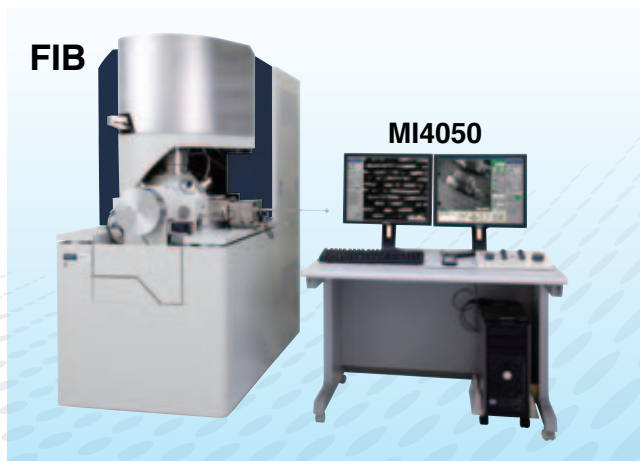
FIB加工
FIB milling



共用試料ホルダ
Compatible sample holder



SEM観察/分析
SEM imaging/analysis



FIB

MI4050



FE-SEM

Regulus
SU8200
SU8010
etc.

FIB : Focused Ion Beam system (集束イオンビーム加工観察装置)
FE-SEM : Field Emission Scanning Electron Microscope (電界放出型走査電子顕微鏡)